

**2000 22nd INTERNATIONAL CONFERENCE
ON MICROELECTRONICS**

PROCEEDINGS



Niš, Yugoslavia
14-17 May 2000

Volume 2

organized by
Yugoslavia IEEE Section - EDS/SSC Chapter

under technical co-sponsorship of the
IEEE Electron Devices Society



IEEE Catalog No. 00TH8400

73.75083

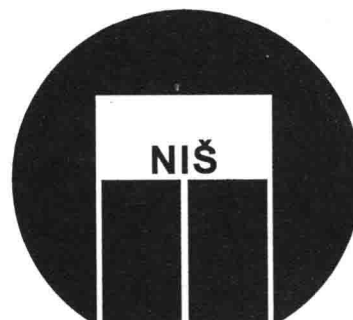
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Published by the

ELECTRON DEVICES SOCIETY

of the

INSTITUTE OF ELECTRICAL AND ELECTRONICS ENGINEERS, INC.

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IEEE Catalog Number 00TH8400
ISBN 0-7803-5235-1 (Softbound Edition)
ISBN 0-7803-5236-X (Microfiche Edition)
Library of Congress Number 98-89413

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